

N-SGT Enhancement Mode MOSFET

General Description

The NVMFS5C646NLWFAFT1G use advanced SGT
MOSFET technology to provide low RDS(ON), low gate
charge, fast switching and excellent avalanche characteristics.
This device is specially designed to get better ruggedness

General Features

V_{DS} =60V l_D =100A

and suitable.

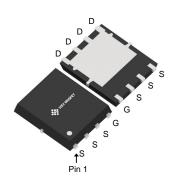
 $R_{DS(ON)} < 5m\Omega$ @ V_{GS} =10V

Applications

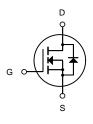
Consumer electronic power supply Motor control

Synchronous-rectification Isolated DC

Synchronous-rectification applications



DFN5X6-8L



N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
NVMFS5C646NLWFAFT1G	DFN5X6-8L	HXY MOSFET	5000

Absolute Maximum Ratings (Tc =25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
V _D S	Drain-Source Voltage	60	V
Vgs	Gate-Source Voltage	±20	V
In@Tc=25°C	Continuous Drain Current, V _{GS} @ 10V	100	А
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V	64	А
Ірм	Pulsed Drain Current ²	385	А
EAS	Single Pulse Avalanche Energy ³	80	mJ
P _D @T _C =25°C	Total Power Dissipation ⁴	73.5	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
Rejc	Thermal Resistance from Junction-to-Ambient ³	1.7	°C/W
Reja	Thermal Resistance Junction-Ambient ¹	51	°C/W

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Electrical Characteristics (T_J = 25°C, unless otherwise noted)

Parameter		Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Drain-Source Breakdown Voltage		V _{(BR)DSS}	V _{GS} = 0V, I _D = 250μA	60	-	-	V
Gate-body Leakage Current		I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
Zero Gate Voltage Drain	T _J =25°C	1	V _{DS} = 60V, V _{GS} = 0V	-	-	1	μΑ
Current	T _J =100°C	IDSS		-	-	100	
Gate-Threshold Voltage		V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250µA	2	2.9	4	V
Drain-Source On-Resistance ⁴		R _{DS(on)}	V _{GS} = 10V, I _D = 21A	-	3.7	5	mΩ
Forward Transconductance	Forward Transconductance ⁴		V _{DS} = 10V, I _D = 21A	-	89	-	S
Input Capacitance	Input Capacitance			-	1673	-	pF
Output Capacitance		Coss	V _{DS} = 30V, V _{GS} =0V, f =1MHz	-	773	-	
Reverse Transfer Capacitance		Crss		-	46.8	-	
Gate Resistance		Rg	f = 1MHz	-	1.8	-	Ω
Total Gate Charge	Total Gate Charge			-	28.5	-	nC
Gate-Source Charge		Q _{gs}	$V_{GS} = 10V, V_{DS} = 30V,$ $I_{D} = 21A$	-	7.8	-	
Gate-Drain Charge		Q_{gd}		-	8.4	-	
Turn-On Delay Time		t _{d(on)}		-	11.2	-	. ns
Rise Time		tr	$V_{GS} = 10V, V_{DD} = 30V,$	-	8.2	-	
Turn-Off Delay Time		t _{d(off)}	$R_G = 3\Omega$, $I_D = 21A$	-	19.6	-	
Fall Time		t f		-	6.2	-	
Body Diode Reverse Recovery Time		t _{rr}	1 - 24 & 41/44-400 &/	-	50	-	ns
Body Diode Reverse Recovery Charge		Q _{rr}	- I _F =21A, dl/dt=100A/μs	-	20	-	nC
Diode Forward Voltage ⁴		V _{SD}	I _S = 21A, V _{GS} = 0V	-	-	1.2	V
Continuous Source Curren	t Tc=25°C	Is	-	-	-	100	Α

Notes:

- 1. Repetitive rating, pulse width limited by junction temperature $T_{\text{J(MAX)}}$ =150°C
- 2. The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V,L=0.1mH, I_{AS} =40A.
- 3. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
- 4. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.
- 5. This value is guaranteed by design hence it is not included in the production test.



Typical Characteristics

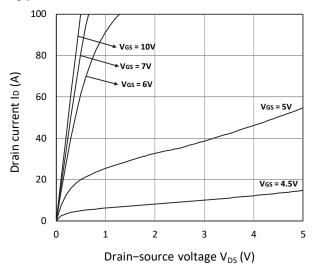


Figure 1. Output Characteristics

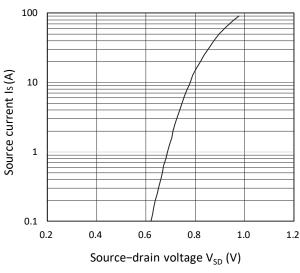


Figure 3. Forward Characteristics of Reverse

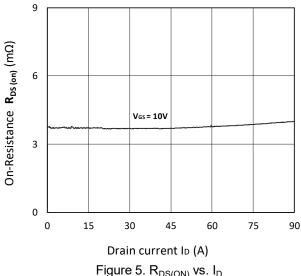


Figure 5. $R_{DS(ON)}$ vs. I_D

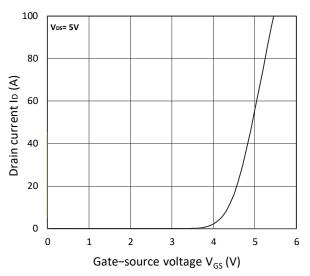


Figure 2. Transfer Characteristics

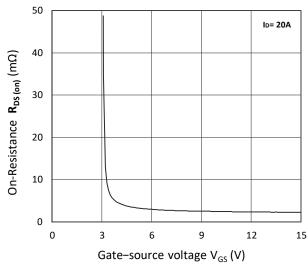


Figure 4. R_{DS(ON)} vs. V_{GS}

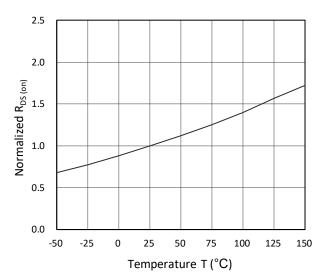


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

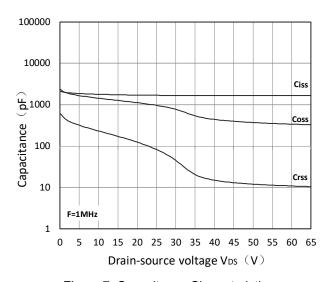


Figure 7. Capacitance Characteristics

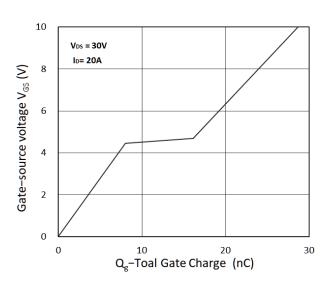


Figure 8. Gate Charge Characteristics

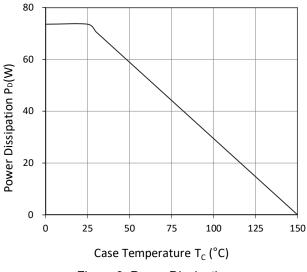


Figure 9. Power Dissipation

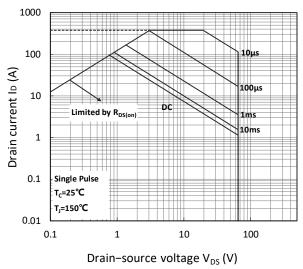


Figure 10. Safe Operating Area

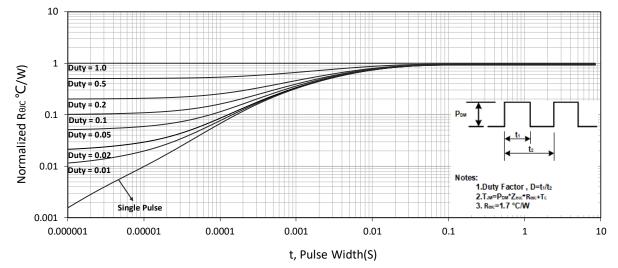


Figure 11. Normalized Maximum Transient Thermal Impedance

Test Circuit

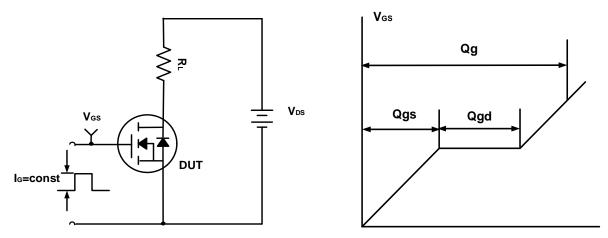


Figure A. Gate Charge Test Circuit & Waveforms

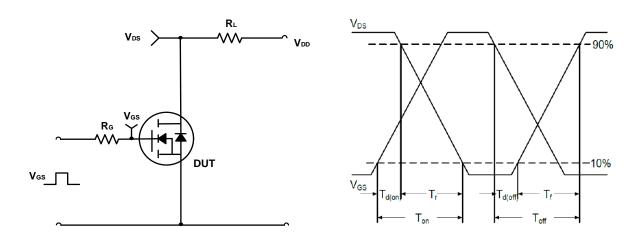


Figure B. Switching Test Circuit & Waveforms

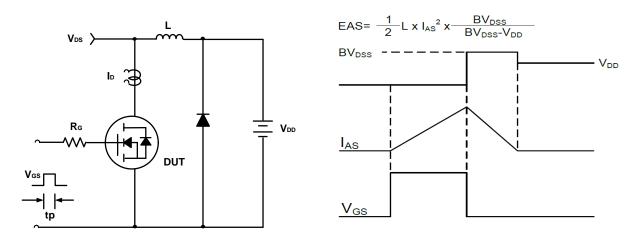
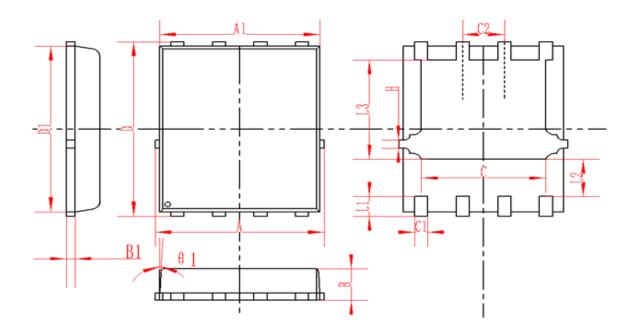


Figure C. Unclamped Inductive Switching Circuit & Waveforms



DFN5X6-8L Package Information



SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX
А	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
В	0.9	0.95	1	0.035	0.037	0.039
B1	0.254REF		0.010REF			
С	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2		1.27TYP			0.5TYP	
θ1	8°	10°	12°	8°	10°	12°
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
Н	0.24	0.25	0.26	0.009	0.010	0.010

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